

Nadeem Ahmed Malik

List of Publications by Year in descending order

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Version: 2024-02-01

10
papers

106
citations

1937685

4
h-index

1872680

6
g-index

10
all docs

10
docs citations

10
times ranked

163
citing authors

#	ARTICLE	IF	CITATIONS
1	Effect of thermal annealing on the structural and optical properties of ZnO thin films deposited by the reactive e-beam evaporation technique. <i>Physica Scripta</i> , 2010, 82, 065801.	2.5	64
2	Synthesis and characterization of porous crystalline SiC thin films prepared by radio frequency reactive magnetron sputtering technique. <i>Applied Surface Science</i> , 2011, 257, 6923-6927.	6.1	20
3	EUV polarimetry for thin film and surface characterization and EUV phase retarder reflector development. <i>Review of Scientific Instruments</i> , 2018, 89, 015108.	1.3	7
4	Vacuum ultraviolet quarter wave plates based on SnTe/Al bilayer: Design, fabrication, optical and ellipsometric characterization. <i>Applied Surface Science</i> , 2019, 463, 75-81.	6.1	7
5	A table top polarimetric facility for the EUV spectral range: implementations and characterization. <i>Proceedings of SPIE</i> , 2017, , .	0.8	4
6	Experimental Study of Few-Layer Graphene: Optical Anisotropy and Pseudo-Brewster Angle Shift in Vacuum Ultraviolet Spectral Range. <i>Advanced Photonics Research</i> , 2021, 2, 2000207.	3.6	2
7	EUV reflective ellipsometry in laboratory: determination of the optical constants and phase retarder properties of SiO ₂ at hydrogen Lyman- α . , 2019, , .		1
8	Optical performances of new materials in the EUV spectral range: metrology, methods and results. , 2019, , .		1
9	Optical and structural characterization of Nb, Zr, Nb/Zr, Zr/Nb thin films on Si ₃ N ₄ membranes windows. , 2017, , .		0
10	Characterization of optical materials for EUV spectral region: Methods and analysis. <i>AIP Conference Proceedings</i> , 2019, , .	0.4	0